

Final Product/Process Change Notification

Document #: FPCN21458Z1 Issue Date: 24 April 2019

Update to FPCN21458Z - Cancellation of previously announced qualification of ON Semiconductor Carmona, Philippines as additional Final Test Location for NCV51510 products.		
24 April 2019. The previously announced change of FPCN21458Z will not be implemented.		
N/A The previously announced change of FPCN21458Z will not be implemented.		
N/A The previously announced change of FPCN21458Z will not be implemented.		
Active components – Integrated circuits		
Contact your local ON Semiconductor Sales Office or < <u>shannon.riggs@onsemi.com></u>		
N/A – FPCN21458Z is cancelled.		
N/A – FPCN21458Z is cancelled.		
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Contact your local ON Semiconductor Sales Office or < <u>Tomas.Vajter@onsemi.com</u> >.		
This is a Final Product/Process Change Notification (FPCN) sent to customers. FPCNs are issued 12 months prior to implementation of the change or earlier upon customer approval. ON Semiconductor will consider this proposed change and it's conditions acceptable, unless an inquiry is made in writing within 45 days of delivery of this notice. To do so, contact PCN.Support@onsemi.com.		
Type of Change		
Move of all or part of electrical wafer test and/or final test to a different location/site/subcontractor		

Description and Purpose:

This Update is to notify customers the changes previously communicated in FPCN21458Z have been cancelled.

FPCN21458Z included the following description:

"This Final Notification announces to expand Final test capacity of ON Semiconductor Carmona, Philippines as an alternate test location for the NCV51510 family of parts. The same test platform, hardware and test program will be used as in the primary Malaysia test location. Product shipments from ON Semiconductor Carmona, Philippines will begin on 12 December 2016 or earlier upon customer approval."

The change described above will not be implemented.

Reason / Motivation for Change:	N/A		
Anticipated impact on fit, form, function, reliability, product safety or manufacturability	The device has been qualified and validated based on the same Product Specification. The device has successfully passed the qualification tests. Potential impacts can be identified, but due to testing performed by ON Semiconductor in relation to the PCN, associated risks are verified and excluded. No anticipated impacts.		
Sites Affected:	ON Semiconductor Sites: ON Seremban, Malaysia	External Foundry/Subcon Sites: None	

TEM001794 Rev. B Page 1 of 2



Current Part Number

NCV51510MNTAG

NCP51510MNTAG

Final Product/Process Change Notification Document #: FPCN21458Z1

Qualification Vehicle

NCV51510MNTAG

NCP51510MNTAG

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Marking of Parts/ Traceability of Change:	N/A		
Reliability Data Summary:			
N/A – FPCN21458Z is cancelled.			
Electrical Characteristic Summary:			
Electrical characteristics are not in	npacted.		
List of Affected Parts:			
	nelf) part numbers are listed in the parts list. Any custom parts affected by this PCN are shown in the customer I email notification, or on the PCN Customized Portal .		

TEM001794 Rev. B Page 2 of 2



Appendix A: Changed Products

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Product	Customer Part Number	New Part Number	Qualification Vehicle
NCP51510MNTAG		NA	NCP51510MNTAG
NCV51510MNTAG		NA	NCV51510MNTAG